

Publikationen

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- (2018): Advances in Electrical and Thermal Characterization of Surfaces and Thin Films. Invited Talk. In: 4th Ed. Smart Materials and Surfaces - SMS Conference 2018, Venedig, Italien.
- (2018): Protective nanometer films for reliable Cu-Cu connections. Invited Talk. In: IEEE International Reliability Physics Symposium (IRPS), San Francisco, CA, USA.
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